INTEGRATED CIRCUITS



Product specification IC15 Data Handbook 1996 Jan 05



Philips Semiconductors

74F153

FEATURES

- Non-inverting outputs
- Separate enable for each section
- Common select inputs
- See 74F253 for 3-State version

DESCRIPTION

The 74F153 is a dual 4-input multiplexer that can select 2 bits of data from up to four sources selected by common Select inputs (S0, S1). The two 4-input multiplexer circuits have individual active-Low Enables (Ea, Eb) which can be used to strobe the outputs independently. Outputs (Ya, Yb) are forced Low when the corresponding Enables (Ea, Eb) are High.

The 74F153 is the logic implementation of a 2-pole, 4-position switch where the switch is determined by the logic levels supplied to the common select inputs.

| TYPE | TYPICAL PROPAGATION DELAY | TYPICAL SUPPLY CURRENT (TOTAL) |
|--------|---------------------------------|--------------------------------------|
| 74F153 | 7.0ns | 12mA |

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE



ORDERING INFORMATION

| DESCRIPTION | $\begin{array}{l} \text{COMMERCIAL RANGE} \\ \text{V}_{\text{CC}} = 5\text{V} \pm 10\%, \\ \text{T}_{\text{amb}} = 0^{\circ}\text{C to} + 70^{\circ}\text{C} \end{array}$ | PKG. DWG. # | | |
|--------------------|---|----------------|--|--|
| 16-pin plastic DIP | N74F153N | SOT38-4 | | |
| 16-pin plastic SO | N74F153D | SOT109-1 | | |

| PINS | DESCRIPTION | 74F (U.L.) HIGH/LOW | LOAD VALUE HIGH/LOW |
|-----------|----------------------------------|---------------------|---------------------|
| 10a – 13a | Port A data inputs | 1.0/1.0 | 20µA/0.6mA |
| 10b – 13b | Port B data inputs | 1.0/1.0 | 20µA/0.6mA |
| S0, S1 | Common Select inputs | 1.0/1.0 | 20µA/0.6mA |
| Ēa | Port A Enable input (active Low) | 1.0/1.0 | 20µA/0.6mA |
| Ēb | Port B Enable input (active Low) | 1.0/1.0 | 20µA/0.6mA |
| Ya, Yb | Port A, B data outputs | 50/33 | 1.0μΑ/20mA |

NOTE: One (1.0) FAST unit load is defined as: 20µA in the High state and 0.6mA in the Low state.

LOGIC SYMBOL



IEC/IEEE SYMBOL



LOGIC DIAGRAM



FUNCTION TABLE

| | | | INPUTS | | | | OUTPUT |
|----|----|----|--------|-----|-----|-----|--------|
| S0 | S1 | Ēn | l0n | l1n | l2n | l3n | Yn |
| Х | Х | н | Х | Х | Х | Х | L |
| L | L | L | L | х | х | х | L |
| L | L | L | н | х | х | х | Н |
| н | L | L | х | L | х | х | L |
| н | L | L | х | н | х | х | Н |
| L | н | L | х | х | L | х | L |
| L | н | L | Х | х | н | х | Н |
| Н | н | L | Х | х | х | L | L |
| Н | н | L | Х | Х | Х | Н | Н |

H = High voltage level L = Low voltage level X = Don't care

74F153

ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

| SYMBOL | PARAMETER | RATING | UNIT |
|------------------|--|------------------|------|
| V _{CC} | Supply voltage | -0.5 to +7.0 | V |
| V _{IN} | Input voltage | -0.5 to +7.0 | V |
| I _{IN} | Input current | -30 to +5 | mA |
| V _{OUT} | Voltage applied to output in High output state | –0.5 to V_{CC} | V |
| I _{OUT} | Current applied to output in Low output state | 40 | mA |
| T _{amb} | Operating free-air temperature range | 0 to +70 | °C |
| T _{stg} | Storage temperature range | -65 to +150 | °C |

RECOMMENDED OPERATING CONDITIONS

| SYMBOL | DADAMETED | | UNIT | | | |
|------------------|--------------------------------------|-----|------|-----|------|--|
| STMBOL | PARAMETER | MIN | NOM | MAX | UNIT | |
| V _{CC} | Supply voltage | 4.5 | 5.0 | 5.5 | V | |
| V _{IH} | High-level input voltage | 2.0 | | | V | |
| V _{IL} | Low-level input voltage | | | 0.8 | V | |
| I _{IK} | Input clamp current | | | -18 | mA | |
| I _{OH} | High-level output current | | | -1 | mA | |
| I _{OL} | Low-level output current | | | 20 | mA | |
| T _{amb} | Operating free-air temperature range | 0 | | +70 | °C | |

DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

| SYMBOL | PARAMETER | | TEST COND | | | | UNIT | | |
|-----------------|---|------------------|------------------------------|------------------------------|-------|------|------|----|--|
| STMBOL | | | TESTCOND | TEST CONDITIONS ¹ | | | MAX | | |
| M | High-level output voltage | | $V_{CC} = MIN, V_{IL} = MAX$ | $\pm 10\% V_{CC}$ | 2.5 | | | v | |
| V _{OH} | High-level output voltage | | $V_{IH} = MIN, I_{OH} = MAX$ | ±5%V _{CC} | 2.7 | 3.4 | | v | |
| Max | Low-level output voltage | | $V_{CC} = MIN, V_{IL} = MAX$ | ±10%V _{CC} | | 0.30 | 0.50 | v | |
| V _{OL} | | | $V_{IH} = MIN, I_{OL} = MAX$ | ±5%V _{CC} | | 0.30 | 0.50 | v | |
| V _{IK} | Input clamp voltage | | $V_{CC} = MIN, I_I = I_{IK}$ | | -0.73 | -1.2 | V | | |
| l _l | Input current at maximum inpu | it voltage | $V_{CC} = MAX, V_I = 7.0V$ | | | 100 | μA | | |
| I _{IH} | High-level input current | | $V_{CC} = MAX, V_I = 2.7V$ | | | 20 | μΑ | | |
| IIL | Low-level input current | | $V_{CC} = MAX, V_I = 0.5V$ | | | | -0.6 | mA | |
| I _{OS} | Short-circuit output current ³ | | V _{CC} = MAX | | -60 | | -150 | mA | |
| Icc | Supply current (total) | | V _{CC} = MAX | Ēn = GND, Sn=In=4.5V | | 12 | 20 | mA | |
| | | I _{CCL} | | En=Sn=In=GND | | 12 | 20 | mA | |

NOTES:

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.

^{2.} All typical values are at $V_{CC} = 5V$, $T_{amb} = 25^{\circ}C$. 3. Not more than one output should be shorted at a time. For testing I_{OS} , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

74F153

AC ELECTRICAL CHARACTERISTICS

| SYMBOL | PARAMETER | TEST CONDITION | V_{CC} = +5.0V T _{amb} = +25°C C _L = 50pF, R _L = 500Ω | | | V _{CC} = +5. T _{amb} = 0°C C _L = 50pF, | UNIT | |
|--------------------------------------|-------------------------------|-------------------|--|------------|--------------|---|--------------|----|
| | | | MIN | ТҮР | MAX | MIN | MAX | |
| t _{PLH} t _{PHL} | Propagation delay In to Yn | Waveform 1 | 3.0 3.0 | 4.5 5.0 | 7.0 7.5 | 2.5 2.5 | 8.0 8.0 | ns |
| t _{PLH} t _{PHL} | Propagation delay Sn to Yn | Waveform 2 | 5.0 5.0 | 8.0 8.0 | 10.5 10.5 | 4.5 4.5 | 12.0 12.0 | ns |
| t _{PLH} t _{PHL} | Propagation delay En to Yn | Waveform 2 | 5.0 4.0 | 7.5 5.5 | 9.0 7.0 | 4.5 3.5 | 10.5 8.0 | ns |

AC WAVEFORMS

For all waveforms, $V_M = 1.5V$.



Waveform 1. Propagation Delay, Data to Output



Waveform 2. Propagation Delay, Enable and Select to Output

TEST CIRCUIT AND WAVEFORMS



DEFINITIONS:

R_L = Load resistor;

 see AC ELECTRICAL CHARACTERISTICS for value.

 CL
 Load capacitance includes jig and probe capacitance; see AC ELECTRICAL CHARACTERISTICS for value.

 $\begin{array}{l} \text{see AC ELECTRICAL CHARACTERISTICS for value} \\ \text{R}_{\text{T}} = & \text{Termination resistance should be equal to } \text{Z}_{\text{OUT}} \text{ of} \\ \text{pulse generators.} \end{array}$



Input Pulse Definition

| fomily | INPUT PULSE REQUIREMENTS | | | | | | |
|--------|--------------------------|----------------------------------|------|-------|------------------|------------------|--|
| family | amplitude | olitude V _M rep. rate | | tw | t _{TLH} | t _{THL} | |
| 74F | 3.0V | 1.5V | 1MHz | 500ns | 2.5ns | 2.5ns | |

SF00006





| UNIT | A max. | A ₁ min. | A ₂ max. | b | b ₁ | b ₂ | с | D ⁽¹⁾ | E ⁽¹⁾ | e | e ₁ | L | ME | M _H | w | Z ⁽¹⁾ max. |
|--------|-----------|------------------------|------------------------|----------------|----------------|----------------|----------------|------------------|------------------|------|----------------|--------------|--------------|----------------|-------|--------------------------|
| mm | 4.2 | 0.51 | 3.2 | 1.73 1.30 | 0.53 0.38 | 1.25 0.85 | 0.36 0.23 | 19.50 18.55 | 6.48 6.20 | 2.54 | 7.62 | 3.60 3.05 | 8.25 7.80 | 10.0 8.3 | 0.254 | 0.76 |
| inches | 0.17 | 0.020 | 0.13 | 0.068 0.051 | 0.021 0.015 | 0.049 0.033 | 0.014 0.009 | 0.77 0.73 | 0.26 0.24 | 0.10 | 0.30 | 0.14 0.12 | 0.32 0.31 | 0.39 0.33 | 0.01 | 0.030 |

Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

| OUTLINE | REFERENCES | | | | EUROPEAN | ISSUE DATE |
|---------|------------|-------|------|--|------------|----------------------------------|
| VERSION | IEC | JEDEC | EIAJ | | PROJECTION | ISSUE DATE |
| SOT38-4 | | | | | | -92-11-17 95-01-14 |

74F153

SOT38-4

74F153



74F153

Data sheet status

| Data sheet status | Product status | Definition [1] |
|---------------------------|-------------------|---|
| Objective specification | Development | This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice. |
| Preliminary specification | Qualification | This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product. |
| Product specification | Production | This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product. |

[1] Please consult the most recently issued datasheet before initiating or completing a design.

Definitions

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

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